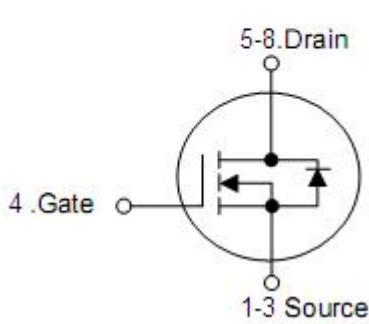
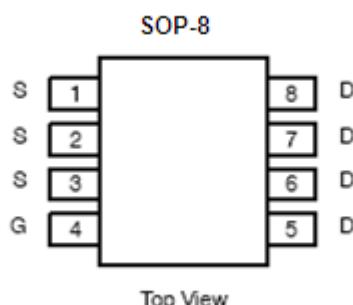


1. Features

- $R_{DS(ON)}=20m\Omega @ V_{GS}=10V$
- N-Channel, Logic level 5V
- Enhancement mode
- Very low on-resistance $R_{DS(ON)} @ V_{GS}=4.5V$
- Fast Switching
- Pb-free lead plating; RoHS compliant

2. Symbol



Pin	Function
1	Source
2	Source
3	Source
4	Gate
5	Drain
6	Drain
7	Drain
8	Drain

3. Maximum ratings, at $T_J=25^\circ\text{C}$, unless otherwise specified

Parameter	Symbol	Rating	Units
Drain-source breakdown voltage	V_{DSS}	100	V
Gate-source voltage $T_C=25^\circ\text{C}$	V_{GS}	± 20	V
Diode continuous forward current	I_S	9	A
Continuous drain current , $V_{GS}@10\text{V}$	I_D	9	A
$T_C=25^\circ\text{C}$		5.8	
Pulsed drain current tested ¹ $T_C=25^\circ\text{C}$	I_{DM}	36	
Maximum power dissipation	P_D	2	W
Avalanche energy, single pulsed ² $L=0.3\text{mH}$	E_{AS}	15	mJ
Storage and operating temperature range	$T_{STG} T_J$	-55 to 175	°C

4. Thermal characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal resistance junction-case	$R_{\theta JC}$	-	35	°C/W
Thermal resistance junction-ambient	$R_{\theta JA}$	-	62.5	

5. Electrical characteristics

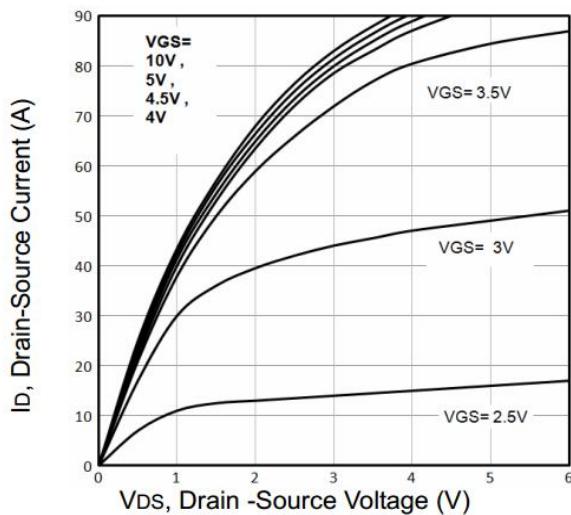
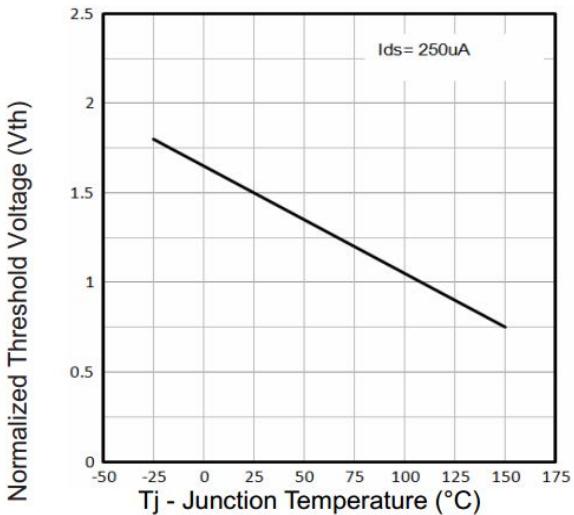
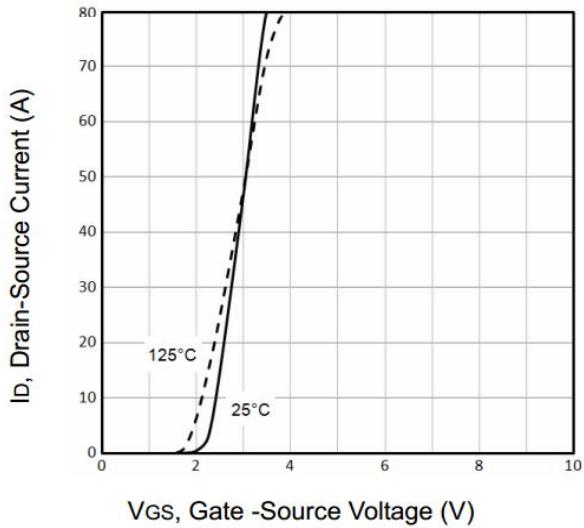
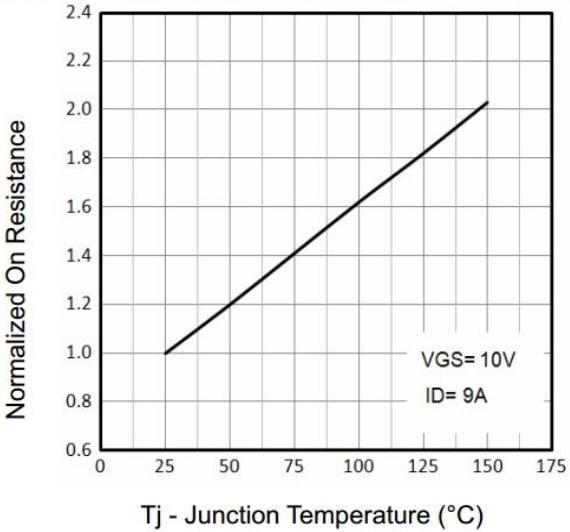
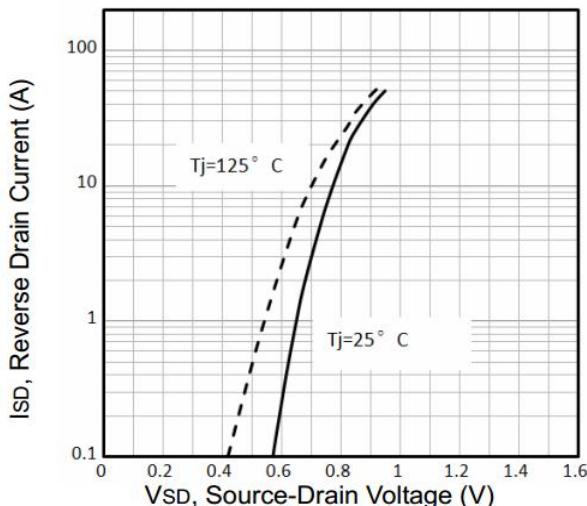
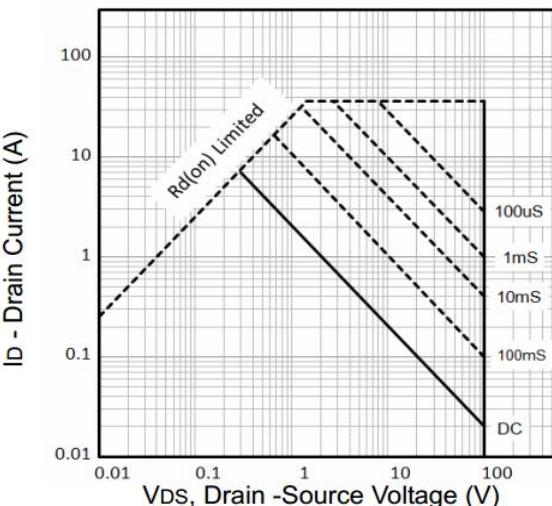
($T_C=25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV_{DSS}	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	100	-	-	V
Drain-source on-resistance ³	$\text{R}_{\text{DS}(\text{on})}$	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=9\text{A}$	-	20	25	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=5\text{A}$	-	22	28	
Gate threshold voltage	$\text{V}_{\text{GS}(\text{TH})}$	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1.0	1.5	2.2	V
Zero gate voltage Drain Current	I_{DSS}	$\text{V}_{\text{DS}}=100\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_C=25^\circ\text{C}$	-	-	1	μA
		$\text{V}_{\text{DS}}=100\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_C=125^\circ\text{C}$	-	-	100	
Gate-source forward leakage	I_{GSS}	$\text{V}_{\text{GS}}=+20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	+100	nA
Total gate charge	Q_g	$\text{V}_{\text{DS}}=50\text{V}, \text{I}_D=8\text{A}$ $\text{V}_{\text{GS}}=10\text{V}$	-	23	-	nC
Gate-source charge	Q_{gs}		-	6.5	-	
Gate-drain charge	Q_{gd}		-	4.5	-	
Turn-on delay time	$t_{\text{d}(\text{on})}$	$\text{V}_{\text{DD}}=50\text{V}, \text{I}_D=8\text{A},$ $\text{R}_G=6.8\Omega, \text{V}_{\text{GS}}=10\text{V}$	-	8	-	ns
Rise time	t_r		-	5	-	
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	26	-	
Fall time	t_f		-	4	-	
Input capacitance	C_{iss}	$\text{V}_{\text{DS}}=24\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $f=1\text{MHz}$	-	1880	-	pF
Output capacitance	C_{oss}		-	145	-	
Reverse transfer capacitance	C_{rss}		-	95	-	
Diode forward voltage	V_{SD}	$\text{I}_{\text{SD}}=2\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	0.71	1.2	V
Reverse recovery time	t_{rr}	$\text{I}_{\text{SD}}=10\text{A}, \text{V}_{\text{GS}}=0\text{V}$ $d\text{I}/dt=100\text{A}/\mu\text{s}$ $T_J=25^\circ\text{C}$	-	24	-	ns
Reverse recovery charge	Q_{rr}		-	50	-	nC

Note:

1. Repetitive rating; pulse width limited by max. junction temperature.
2. Limited by $T_{J\text{MAX}}$, starting $T_J=25^\circ\text{C}$, $L=0.3\text{mH}$, $R_G=25\Omega$, $\text{I}_{\text{AS}}=10\text{A}$, $\text{V}_{\text{GS}}=10\text{V}$, Part not recommended for use above this value.
3. Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$

6. Typical operating characteristics

**Fig1.** Typical Output Characteristics**Fig2.** Normalized Threshold Voltage Vs. Temperature**Fig3.** Typical Transfer Characteristics**Fig4.** Normalized On-Resistance Vs. Temperature**Fig5.** Typical Source-Drain Diode Forward Voltage**Fig6.** Maximum Safe Operating Area

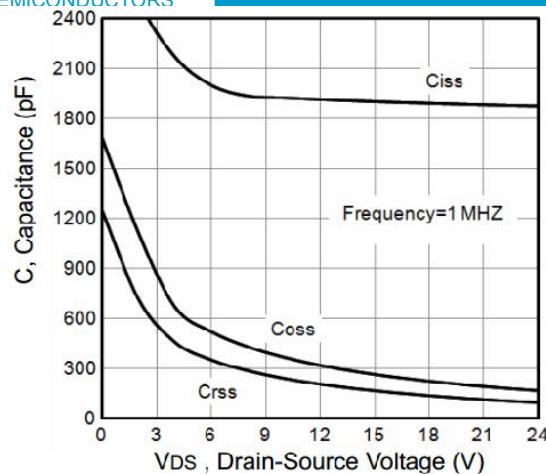


Fig7. Typical Capacitance Vs.Drain-Source Voltage

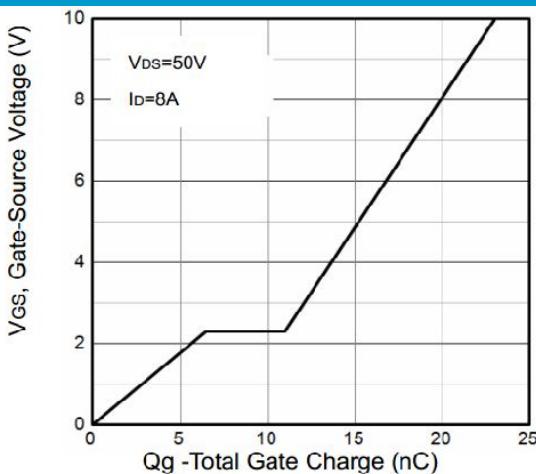


Fig8. Typical Gate Charge Vs.Gate-Source

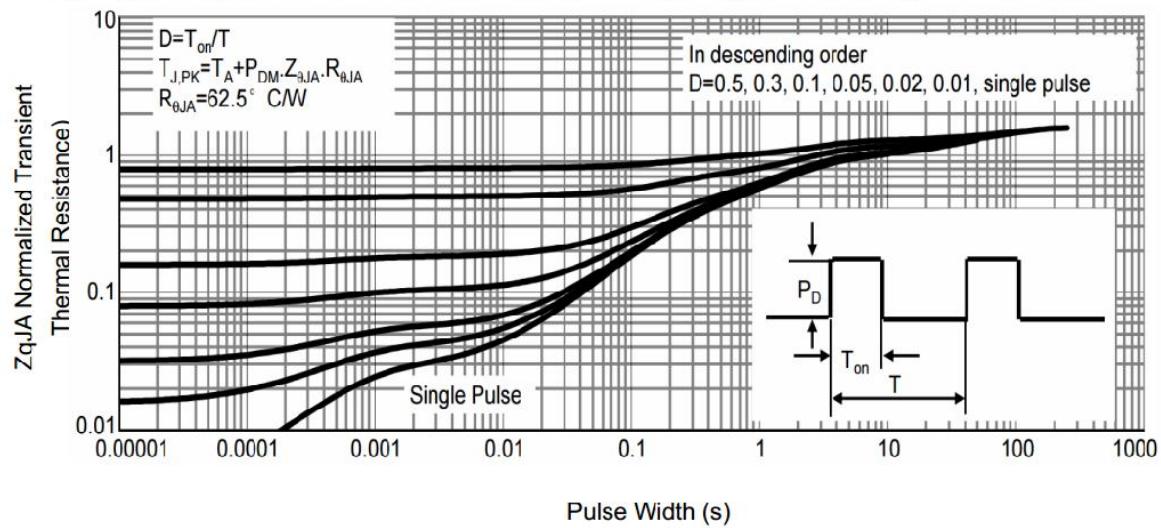


Fig9. Normalized Maximum Transient Thermal Impedance

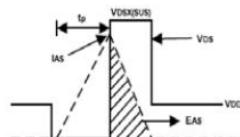
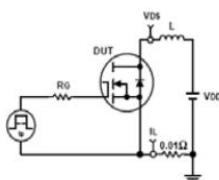


Fig10. Unclamped Inductive Test Circuit and waveforms

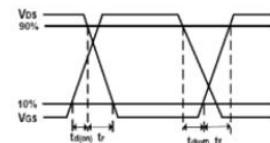
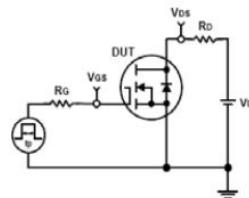


Fig11. Switching Time Test Circuit and waveforms